

FPF30-VB Datasheet

N-Channel 900V (D-S) Super Junction Power MOSFET

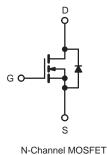
| PRODUCT SUMMARY | | | | | | |
|----------------------------|------------------------|--------|--|--|--|--|
| V _{DS} (V) | 90 | 900 | | | | |
| R _{DS(on)} (Ω) | V _{GS} = 10 V | 1.3 | | | | |
| Q _g (Max.) (nC) | 200 | 200 | | | | |
| Q _{gs} (nC) | 24 | 24 | | | | |
| Q _{gd} (nC) | 110 | 110 | | | | |
| Configuration | Sing | Single | | | | |

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







| ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted) | | | | | | |
|---|-------------------------|-------------------------|-----------------------------------|------------------|----------|--|
| PARAMETER | | | SYMBOL | LIMIT | UNIT | |
| Drain-Source Voltage | | | V_{DS} | 900 | V | |
| Gate-Source Voltage | | | V_{GS} | ± 20 | 7 v | |
| Continuous Drain Current | V _{GS} at 10 V | $T_C = 25 ^{\circ}C$ | I _D | 5 | | |
| Continuous Drain Current | VGS at 10 V | T _C = 100 °C | | 3.9 | Α | |
| Pulsed Drain Current ^a | | | I _{DM} | 21 | 1 | |
| Linear Derating Factor | | | 1.5 | W/°C | | |
| Single Pulse Avalanche Energy ^b | | E _{AS} | 770 | mJ | | |
| Repetitive Avalanche Currenta | I _{AR} | 7.8 | Α | | | |
| Repetitive Avalanche Energy ^a | | | E _{AR} | 19 | mJ | |
| Maximum Power Dissipation T _C = 25 °C | | | P _D | 190 | W | |
| Peak Diode Recovery dV/dt ^c | | dV/dt | 2.0 | V/ns | | |
| Operating Junction and Storage Temperature Range | | | T _J , T _{stg} | - 55 to + 150 | °C | |
| Soldering Recommendations (Peak Temperature) for 10 s | | | | 300 ^d | | |
| Mounting Torque | 6-32 or N | 13 screw | | 10 | lbf ⋅ in | |
| Mounting rorque | 6-32 or M3 screw | | | 1.1 | N⋅m | |

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_{J} = 25$ °C, L = 23 mH, $R_{g} = 25$ Ω , $I_{AS} = 7.8$ A (see fig. 12). c. $I_{SD} \le 7.8$ A, dl/dt ≤ 140 A/ μ s, $V_{DD} \le 600$ V, $T_{J} \le 150$ °C. d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



| THERMAL RESISTANCE RATINGS | | | | | |
|-------------------------------------|-------------------|------|------|------|--|
| PARAMETER | SYMBOL | TYP. | MAX. | UNIT | |
| Maximum Junction-to-Ambient | R _{thJA} | - | 40 | | |
| Case-to-Sink, Flat, Greased Surface | R _{thCS} | 0.24 | - | °C/W | |
| Maximum Junction-to-Case (Drain) | R _{thJC} | - | 0.65 | | |

| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
|---|-----------------------|--|--|------|------|------------------|------|
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V _{DS} | $V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$ | | 900 | - | - | V |
| V _{DS} Temperature Coefficient | $\Delta V_{DS}/T_{J}$ | Reference | e to 25 °C, I _D = 1 mA | - | 0.98 | - | V/°C |
| Gate-Source Threshold Voltage | V _{GS(th)} | V _{DS} : | = V _{GS} , I _D = 250 μA | 2.0 | - | 4.0 | V |
| Gate-Source Leakage | I _{GSS} | | V _{GS} = ± 20 V | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | | V _{DS} : | V _{DS} = 800 V, V _{GS} = 0 V | | - | 100 | ,., |
| Zero date voltage Brain ourient | I _{DSS} | $V_{DS} = 640 \text{V}$ | $V, V_{GS} = 0 V, T_{J} = 125 ^{\circ}C$ | - | - | 500 | μA |
| Drain-Source On-State Resistance | R _{DS(on)} | V _{GS} = 10 V | $I_D = 3.7 A^b$ | - | 1.3 | - | Ω |
| Forward Transconductance | g _{fs} | V _{DS} = | = 100 V, I _D = 3.7 A ^b | 5.6 | - | - | S |
| Dynamic | | | | | | | |
| Input Capacitance | C_{iss} | | V _{GS} = 0 V, | | 3100 | - | |
| Output Capacitance | C _{oss} | | $V_{DS} = 25 \text{ V},$ | - | 800 | - | pF |
| Reverse Transfer Capacitance | C_{rss} | f = 1 | .0 MHz, see fig. 5 | - | 490 | - | |
| Total Gate Charge | Q_g | | | - | - | 200 | nC |
| Gate-Source Charge | Q_gs | $V_{GS} = 10 \text{ V}$ | $I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b | - | - | 24 | |
| Gate-Drain Charge | Q_{gd} | | | - | - | 110 | |
| Turn-On Delay Time | t _{d(on)} | V_{DD} = 400 V, I_{D} = 3.8 A, R_{g} = 6.2 Ω , R_{D} = 52 Ω see fig. 10 ^b | | - | 19 | - | - ns |
| Rise Time | t _r | | | - | 38 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | - | 120 | - | |
| Fall Time | t _f | | | - | 39 | - | |
| Internal Drain Inductance | L_D | Between lead, 6 mm (0.25") from package and center of die contact | | - | 5.0 | - | الم |
| Internal Source Inductance | L _S | | | - | 13 | - | - nH |
| Drain-Source Body Diode Characteristic | s | • | | | | · | |
| Continuous Source-Drain Diode Current | I _S | MOSFET symbol showing the integral reverse p - n junction diode | | - | - | 5.0 | |
| Pulsed Diode Forward Current ^a | I _{SM} | | | - | - | 21 | A |
| Body Diode Voltage | V _{SD} | $T_J = 25 ^{\circ}\text{C}, I_S = 3.8 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$ | | - | - | 1.8 | V |
| Body Diode Reverse Recovery Time | t _{rr} | $T_J = 25 ^{\circ}\text{C}, I_F = 3.8 \text{A},$ | | - | 650 | 980 | ns |
| Body Diode Reverse Recovery Charge | Q _{rr} | $dI/dt = 100 \text{ A/µs}^b$ | | - | 3.8 | 5.7 | μC |
| Forward Turn-On Time | t _{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D) | | | | L _D) | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

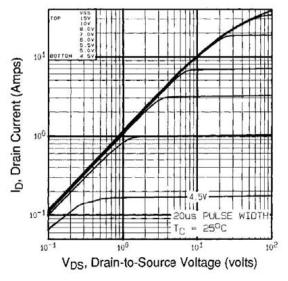


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

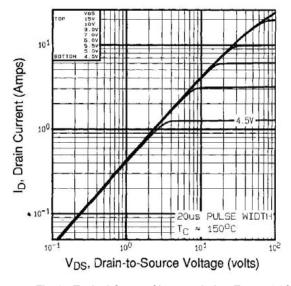


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

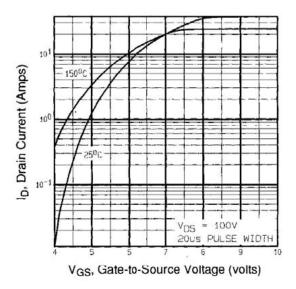


Fig. 3 - Typical Transfer Characteristics

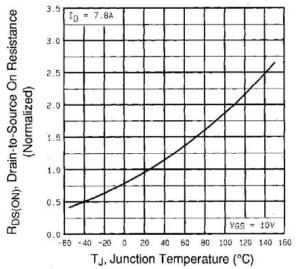


Fig. 4 - Normalized On-Resistance vs. Temperature



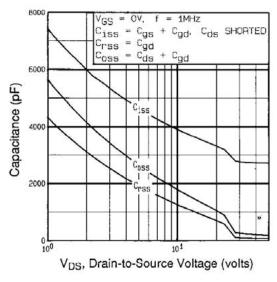


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

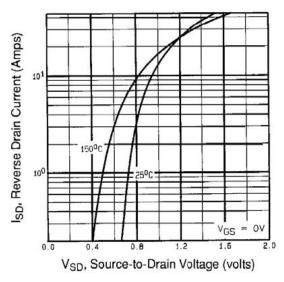


Fig. 7 - Typical Source-Drain Diode Forward Voltage

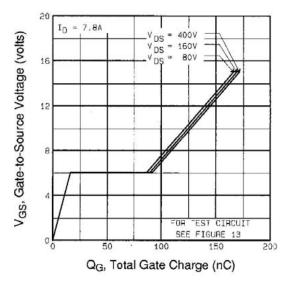


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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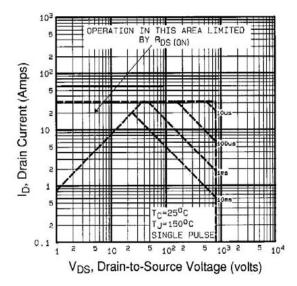


Fig. 8 - Maximum Safe Operating Area



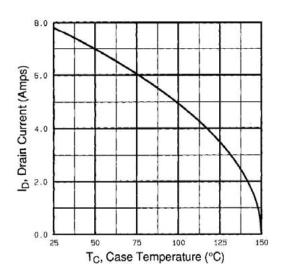


Fig. 9 - Maximum Drain Current vs. Case Temperature

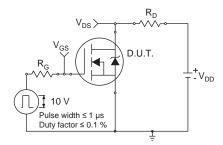


Fig. 10a - Switching Time Test Circuit

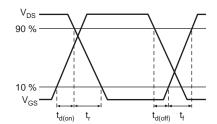


Fig. 10b - Switching Time Waveforms

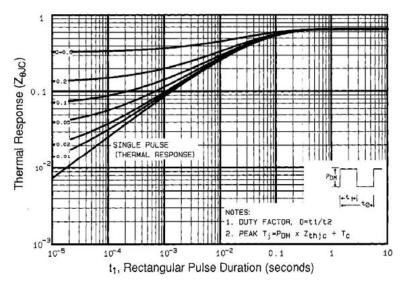


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



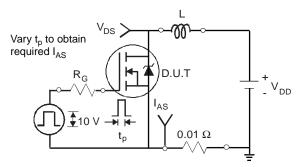


Fig. 12a - Unclamped Inductive Test Circuit

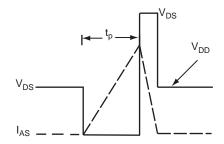


Fig. 12b - Unclamped Inductive Waveforms

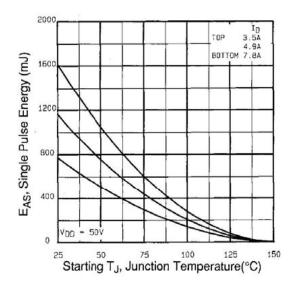


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

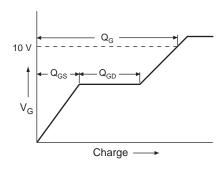


Fig. 13a - Basic Gate Charge Waveform

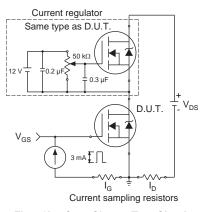
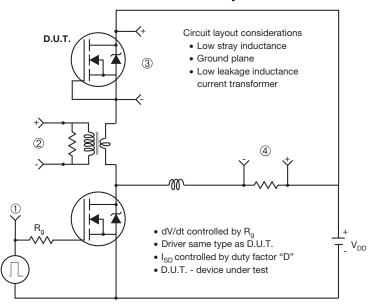


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



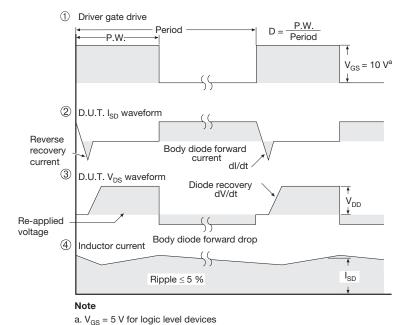
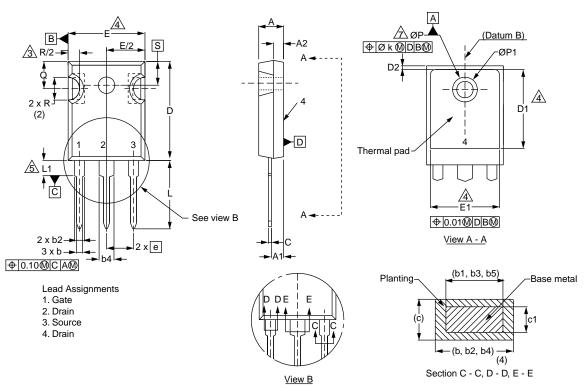


Fig. 14 - For N-Channel



TO-247AC (High Voltage)



| | MILLIM | IETERS | INC | HES |
|------|--------|--------|-------|-------|
| DIM. | MIN. | MAX. | MIN. | MAX. |
| Α | 4.58 | 5.31 | 0.180 | 0.209 |
| A1 | 2.21 | 2.59 | 0.087 | 0.102 |
| A2 | 1.17 | 2.49 | 0.046 | 0.098 |
| b | 0.99 | 1.40 | 0.039 | 0.055 |
| b1 | 0.99 | 1.35 | 0.039 | 0.053 |
| b2 | 1.53 | 2.39 | 0.060 | 0.094 |
| b3 | 1.65 | 2.37 | 0.065 | 0.093 |
| b4 | 2.42 | 3.43 | 0.095 | 0.135 |
| b5 | 2.59 | 3.38 | 0.102 | 0.133 |
| С | 0.38 | 0.86 | 0.015 | 0.034 |
| c1 | 0.38 | 0.76 | 0.015 | 0.030 |
| D | 19.71 | 20.82 | 0.776 | 0.820 |
| D1 | 13.08 | - | 0.515 | - |

| | MILLIMETERS | | INC | HES | |
|------|-------------|----------|-------|-------|--|
| DIM. | MIN. | MAX. | MIN. | MAX. | |
| D2 | 0.51 | 1.30 | 0.020 | 0.051 | |
| Е | 15.29 | 15.87 | 0.602 | 0.625 | |
| E1 | 13.72 | - | 0.540 | 1 | |
| е | 5.46 | BSC | 0.215 | BSC | |
| Øk | 0.2 | 0.254 | | 0.010 | |
| L | 14.20 | 16.25 | 0.559 | 0.640 | |
| L1 | 3.71 | 4.29 | 0.146 | 0.169 | |
| N | 7.62 | 7.62 BSC | | BSC | |
| ØΡ | 3.51 | 3.66 | 0.138 | 0.144 | |
| Ø P1 | - | 7.39 | ı | 0.291 | |
| Q | 5.31 | 5.69 | 0.209 | 0.224 | |
| R | 4.52 | 5.49 | 0.178 | 0.216 | |
| S | 5.51 BSC | | 0.217 | BSC | |



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